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a second measurement system which measures an amount of positional deviation of each of the plurality of movable stages from a predetermined reference position within the predetermined measurement range, or a degree of coincidence of each of the plurality of movable stages with respect to the reference position, the second measurement system measuring the amount of positional deviation or the degree of coincidence along a first direction that is perpendicular the certain movement plane;

wherein a measurement value obtained with the first measurement system is corrected on the basis of a measurement result of the second measurement system.

11 4. (Twice Amended) A stage device, comprising:

a plurality of movable stages disposed in a certain movement plane so as to be movable independently of each other;

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a first measurement system which measures within a first measurement range a position of one of the plurality of movable stages, the first measurement system being capable of emitting a measurement beam to a mirror of each of the plurality of movable stages;

a second measurement system which continuously measures positions of the plurality of movable stages within a second measurement range partially overlapping the first measurement range; and

a control system which corrects the measurement results of the first and second measurement systems on the basis of the measurement results of the first and second measurement systems.

246. (Twice Amended) A stage device comprising:

a movable stage that is movable at a predetermined degree of freedom;

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an interferometer system which measures an amount of displacement of the movable stage by directing a measurement light at the movable stage and causing a reflected

light thereof to interfere with a reference light, wherein the interferometer system has a plurality of measurement axes of the measurement light and is disposed such that even if one of the plurality of measurement axes is not irradiating the movable stage, the amount of displacement can still be measured by another measurement axis; and

a signal processing system with which, when the one measurement axis changes from the state of not irradiating the movable stage to a state of irradiating the movable stage, a degree of interference of the one measurement axis is estimated from a measurement result for the another measurement axis, and an initial value of the one measurement axis is set on the basis of the estimated degree of interference and a phase measured with the one measurement axis;

wherein the interferometer system measures the amount of displacement of the movable stage in the form of $f(\lambda)\{N + \Phi/(2\pi)\}$ with each of the plurality of measurement axes, where $f(\lambda)$ is a function of the wavelength λ of the measurement light, N is an integer indicating the degree of interference, and Φ is the phase.

Please add the following claim 31:

04 ~~23-31~~ (New) A stage device according to claim 2, wherein the plurality of movable stages pass through a common range in a first direction on the certain movement plane, and the first measurement range includes the common range.--

REMARKS

Claims 1-10, 12-28, 30 and 31 are pending. By this Amendment, claim 31 is added, claims 11 and 29 are canceled, and claims 1, 2 and 10 are amended. The attached Appendix includes a marked-up copy of the rewritten claim (37 C.F.R. 1.121(c)(1)(ii)).

The features of claim 29 have been placed into claim 2. The features of claim 11 have been placed into claim 10. Claim 1 has been amended to even more clearly distinguish over the applied reference by reciting that the second measurement system measures along a first